Special Issue

Knowledge Retrieval and Reuse

Message from the Guest Editors

This Special Issue intends to focus on several aspects around knowledge retrieval and reuse (KR & R), including: - Clarifying the difference between information and knowledge - Modern algorithms for information and knowledge retrieval - Artificial intelligence and KR & R: how machine learning and user feedback affect the retrieval and reuse of all sorts of knowledge artifacts - Applications of KR & R: - Interactive retrieval and reuse: chat boxes / virtual assistants - Beyond the format and domain limit: specific search tools for models, blueprints, molecules, graphs, etc. - Systems engineering retrieval and reuse - Software engineering retrieval and reuse - Information science retrieval and reuse - Ontology and semantic domain

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multidimensional network.

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